

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4995	382/141,145,149,150,190,209,224.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:50
L2	830	348/125,126,128-130.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:50
L3	1627	356/237.2-237.5.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:50
L4	0	345/700.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:50
L5	7034	1 2 3 4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:50
L6	2256869	semiconductor wafer ic (integrated near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 09:22
L7	35755	6 near (inspect\$ defect detect\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:52
L8	4	7 same classif\$ same edit\$	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:53
L9	1204	5 and 7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:53

L10	717	7 same classif\$	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:53
L11	411	10 and (edit\$ modif\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 08:54
L12	1	((semiconductor wafer ic (integrated near circuit)) and (classif\$) and (edit\$) and (defect detect) and (re adj classif\$) and (displa\$)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/08 09:25
L13	1	((semiconductor wafer ic (integrated near circuit)) and (classif\$) and (edit\$) and (defect detect) and (re adj classif\$) and (displa\$)).clm.	US-PGPUB	OR	ON	2005/12/08 09:25

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L13	1	((semiconductor wafer ic (integrated near circuit)) and (classif\$) and (edit\$) and (defect detect) and (re adj classif\$) and (displa\$)).clm.	US-PGPUB	OR	ON	2005/12/08 09:25

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